

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/677,299 | HEO ET AL. | |
| Examiner | | Art Unit | | Page 1 of 1 |
| Erin M. File | | 2611 | | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-4,057,834 A | 11-1977 | Nakagome et al. | 358/426.12 |
| * | B | US-2002/0015438 A1 | 02-2002 | Ishizu et al. | 375/147 |
| * | C | US-6,430,214 B1 | 08-2002 | Jalloul et al. | 375/147 |
| * | D | US-2002/0159507 A1 | 10-2002 | Flaig et al. | 375/148 |
| * | E | US-2002/0177432 A1 | 11-2002 | Casaccia et al. | 455/410 |
| * | F | US-2003/0022636 A1 | 01-2003 | Ylitalo et al. | 455/101 |
| * | G | US-2003/0053524 A1 | 03-2003 | Dent, Paul W. | 375/148 |
| * | H | US-2003/0157897 A1 | 08-2003 | Maeda et al. | 455/67.3 |
| * | I | US-2004/0028121 A1 | 02-2004 | Fitton, Michael P. | 375/144 |
| * | J | US-6,788,733 B1 | 09-2004 | Whang et al. | 375/148 |
| * | K | US-2004/0202151 A1 | 10-2004 | Reznik et al. | 370/352 |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.